Special Issue

Advanced Methods and Applications of Al Diagnostic

Message from the Guest Editor

Al techniques-based diagnostics have the potential to provide high reliability in practical diseases and symptoms management. The rapid growth of medical multimedia data not only gives a chance to improve Al diagnostic quality but also to discover advance knowledge of rare diseases and symptoms. Over the past few years, improvements in computing power and diverse machine learning techniques enable us to process hundreds of thousands of multimedia data and extract expert knowledge for a medical diagnosis. The main topics include but are not limited to the following:

- Advanced methods of medical image processing and analysis
- Early detection and diagnosis methods for diverse symptoms management
- Multimedia big data processing for diagnosis applications
- Pattern recognition techniques for clinical diagnosis
- AI-based symptoms and disease monitoring or management

Guest Editor

Dr. Seungmin Rho

Department of Industrial Security, Chung-Ang University, Seoul 06974, Republic of Korea

Deadline for manuscript submissions

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Applied Sciences Editorial Office MDPI, Grosspeteranlage 5 4052 Basel, Switzerland Tel: +41 61 683 77 34 applsci@mdpi.com

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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multidimensional network.

Editor-in-Chief

Prof. Dr. Giulio Nicola Cerullo

Dipartimento di Fisica, Politecnico di Milano, Piazza L. da Vinci 32, 20133 Milano, Italy

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